



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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企业微信二维码



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Product Summary

BV _{DSS}	R _{DS(on)} Max	I _D Max T _A = +25°C
30V	11mΩ @ V _{GS} = 10V	10.5A
	15mΩ @ V _{GS} = 4.5V	9.2A

Features and Benefits

- Low R_{DS(on)} – Ensures On-State Losses Are Minimized
- 100% Unclamped Inductive Switching, Test in Production – Ensures More Reliable And Robust End Application
- Small Form Factor Thermally Efficient Package Enables Higher Density End Products
- Occupies Just 33% of The Board Area Occupied by SO-8 Enabling Smaller End Product

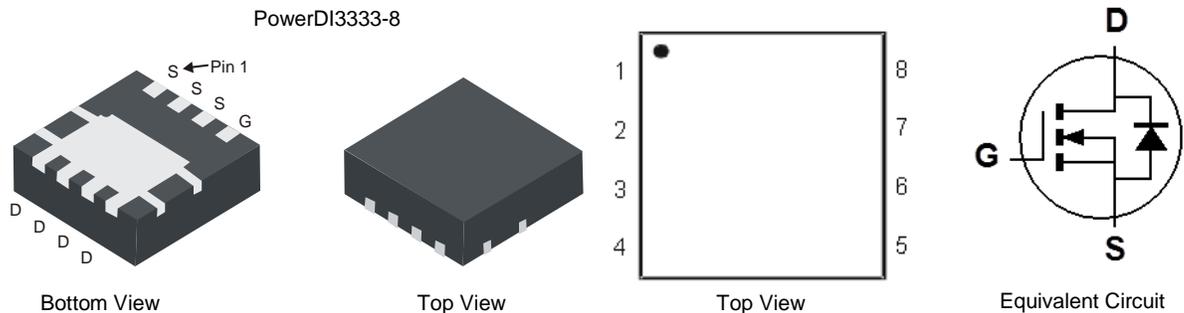
Description and Applications

This MOSFET is designed to meet the stringent requirements of automotive applications. It is qualified to AEC-Q101, supported by a PPAP and is ideal for use in:

- Motor controls
- Power-management functions
- DC-DC converters

Mechanical Data

- Package: PowerDI®3333-8
- Package Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 3 per J-STD-020
- Terminal Connections Indicator: See Diagram
- Terminals: Finish—Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 ③
- Weight: 0.034 grams (Approximate)



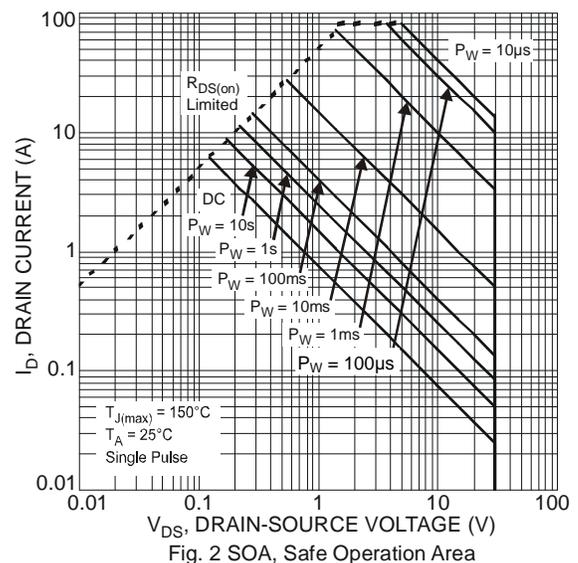
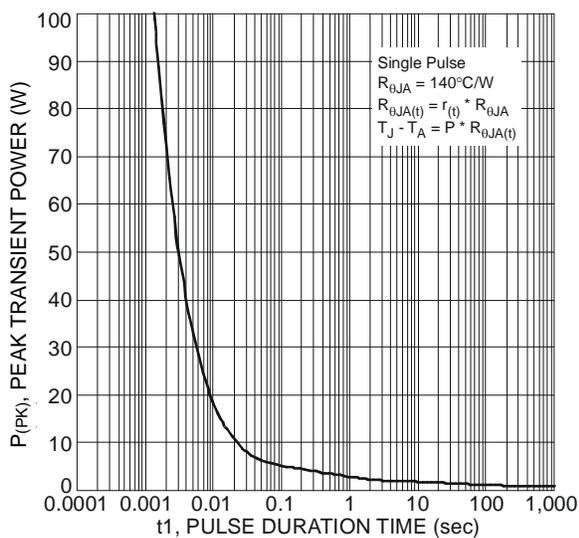
Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Drain-Source Voltage		V_{DSS}	30	V
Gate-Source Voltage		V_{GSS}	± 20	V
Continuous Drain Current (Note 6) $V_{GS} = 10\text{V}$	Steady State $T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	I_D	10.5 8.5	A
	$t < 10\text{s}$ $T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	I_D	14 11	A
Pulsed Drain Current (10 μs Pulse, Duty Cycle = 1%)		I_{DM}	90	A
Maximum Continuous Body Diode Forward Current (Note 6)		I_S	3.0	A
Avalanche Current (Note 7) $L = 0.1\text{mH}$		I_{AR}	22	A
Repetitive Avalanche Energy (Note 7) $L = 0.1\text{mH}$		E_{AR}	24	mJ

Thermal Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	Steady State	P_D	0.9	W
	$t < 10\text{s}$		1.5	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	142	$^\circ\text{C/W}$
	$t < 10\text{s}$		78	
Total Power Dissipation (Note 6)	Steady State	P_D	2.2	W
	$t < 10\text{s}$		3.5	
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	59	$^\circ\text{C/W}$
	$t < 10\text{s}$		33	
Thermal Resistance, Junction to Case (Note 6)		$R_{\theta JC}$	11	
Operating and Storage Temperature Range		T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

- Notes:
- Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
 - Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 - I_{AR} and E_{AR} ratings are based on low frequency and duty cycles to keep $T_J = +25^\circ\text{C}$.



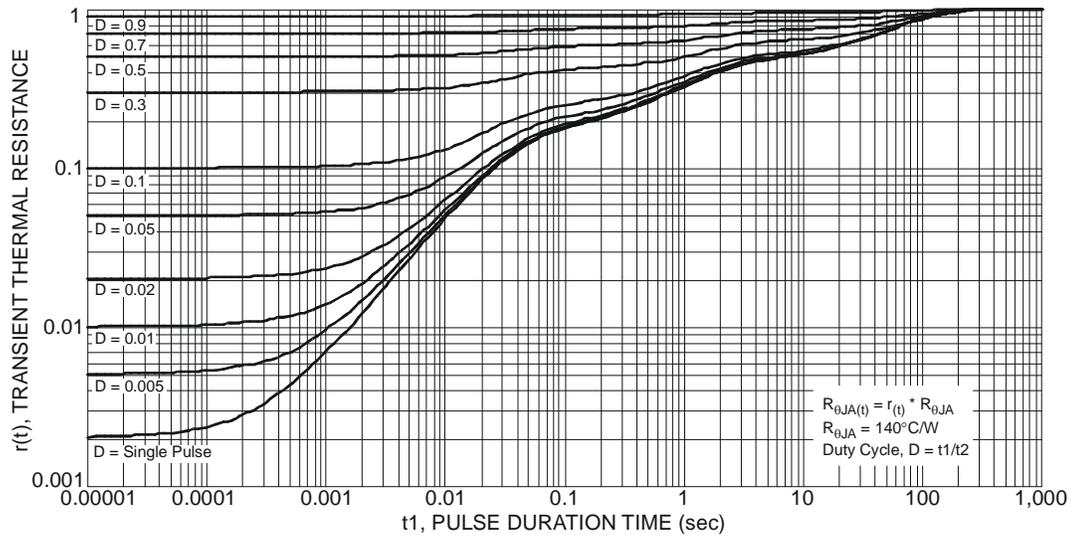


Fig. 3 Transient Thermal Resistance

Electrical Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	1	μA	$V_{DS} = 30V, V_{GS} = 0V$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(th)}$	1.4	—	2.5	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
Static Drain-Source On-Resistance	$R_{DS(on)}$	—	7	11	m Ω	$V_{GS} = 10V, I_D = 20A$
		—	11	15		$V_{GS} = 4.5V, I_D = 20A$
Forward Transfer Admittance	$ Y_{fs} $	—	74	—	S	$V_{DS} = 5V, I_D = 20A$
Diode Forward Voltage	V_{SD}	—	0.75	1.0	V	$V_{GS} = 0V, I_S = 1A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{iss}	—	1281	—	pF	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1.0MHz$
Output Capacitance	C_{oss}	—	145	—	pF	
Reverse Transfer Capacitance	C_{rss}	—	125	—	pF	
Gate Resistance	R_g	—	1.2	—	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge ($V_{GS} = 4.5V$)	Q_g	—	12.5	—	nC	$V_{DS} = 15V, I_D = 12A$
Total Gate Charge ($V_{GS} = 10V$)	Q_g	—	26.7	—	nC	
Gate-Source Charge	Q_{gs}	—	3.6	—	nC	
Gate-Drain Charge	Q_{gd}	—	4.4	—	nC	
Turn-On Delay Time	$t_{D(on)}$	—	5.2	—	ns	$V_{DD} = 15V, V_{GS} = 10V,$ $R_L = 1.25\Omega, R_G = 3\Omega$
Turn-On Rise Time	t_R	—	21.2	—	ns	
Turn-Off Delay Time	$t_{D(off)}$	—	22.3	—	ns	
Turn-Off Fall Time	t_F	—	5.1	—	ns	
Reverse Recovery Time	t_{RR}	—	8.5	—	ns	$I_F = 12A, di/dt = 500A/\mu s$
Reverse Recovery Charge	Q_{RR}	—	7.0	—	nC	$I_F = 12A, di/dt = 500A/\mu s$

Notes: 8. Short duration pulse test used to minimize self-heating effect.
 9. Guaranteed by design. Not subject to product testing.

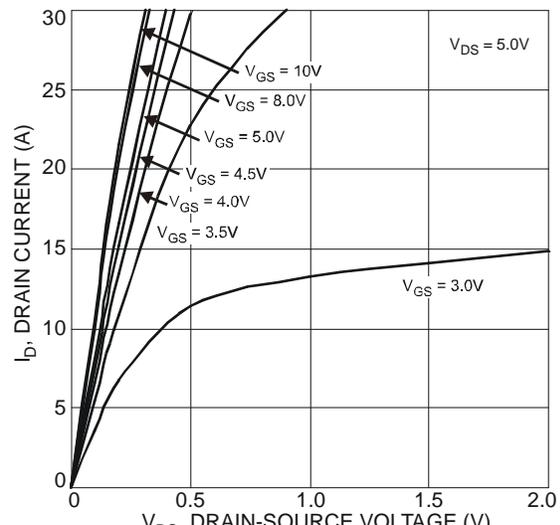


Fig. 4 Typical Output Characteristic

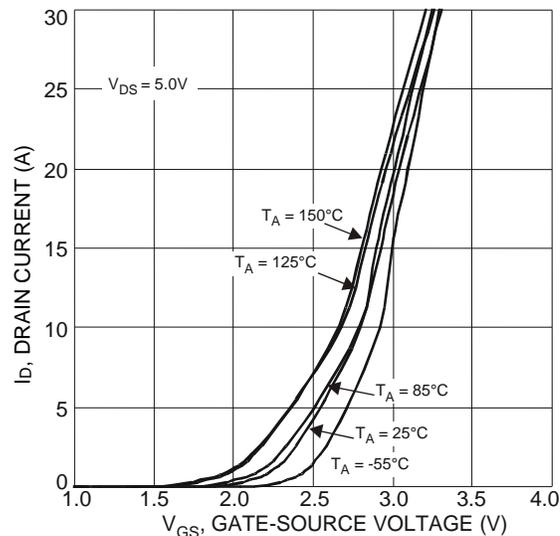


Fig. 5 Typical Transfer Characteristics

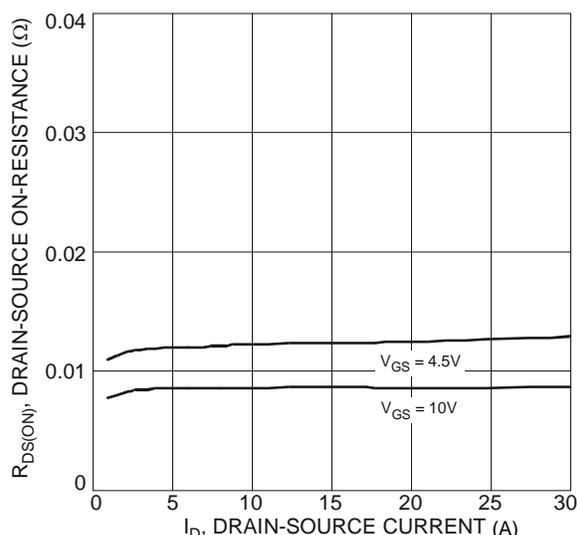


Fig. 6 Typical On-Resistance vs. Drain Current and Gate Voltage

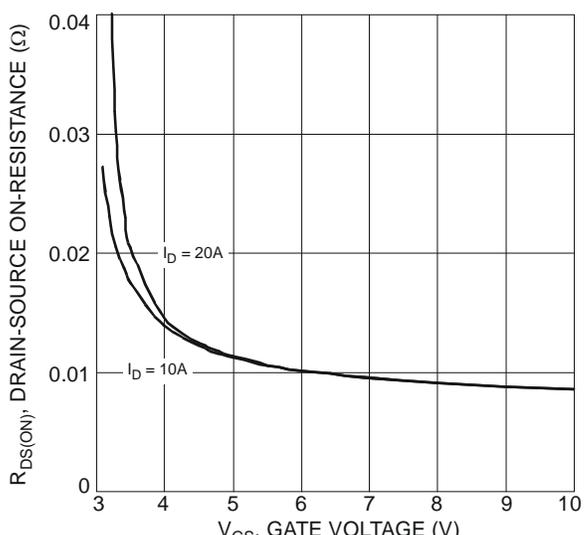


Fig. 7 Typical On-Resistance vs. Gate Voltage

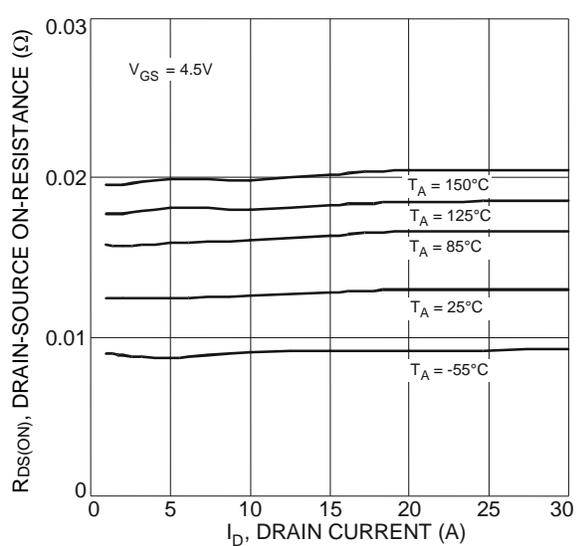


Fig. 8 Typical On-Resistance vs. Drain Current and Temperature

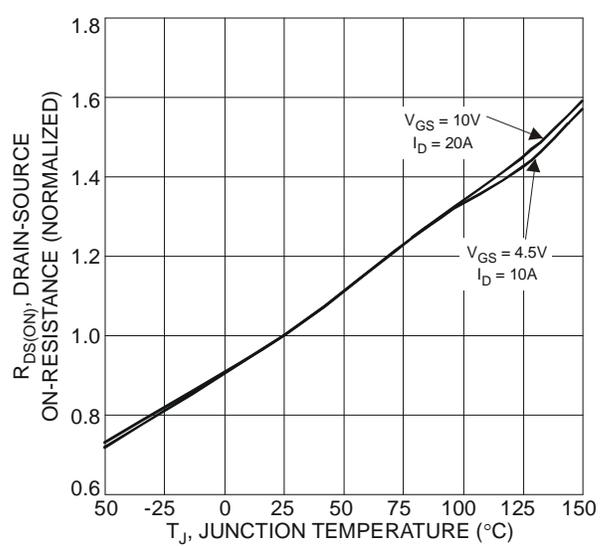


Fig. 9 On-Resistance Variation with Temperature

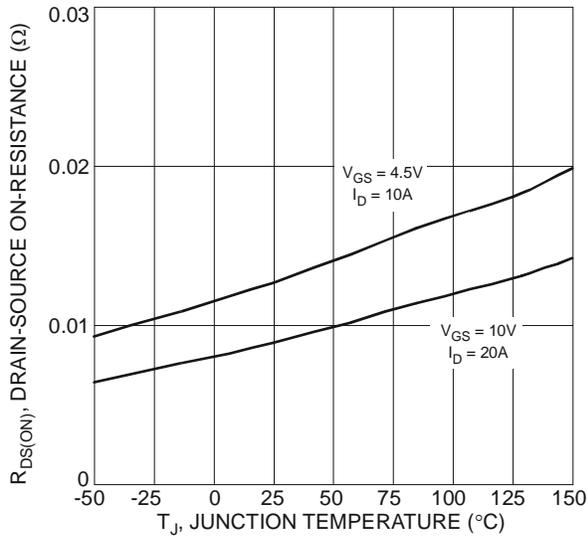


Fig. 10 On-Resistance Variation with Temperature

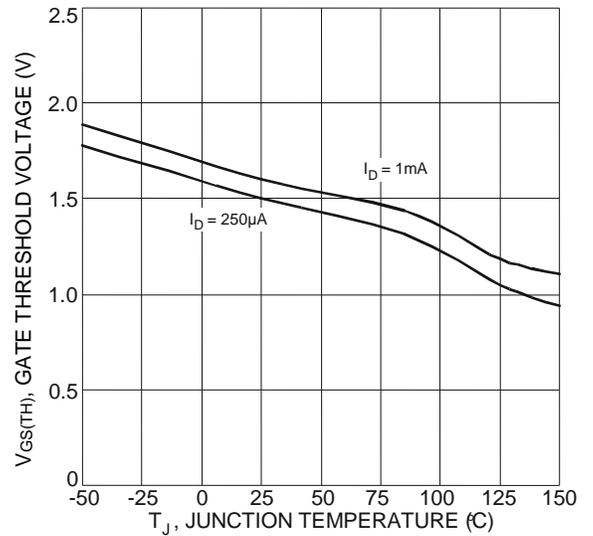


Fig. 11 Gate Threshold Variation vs. Junction Temperature

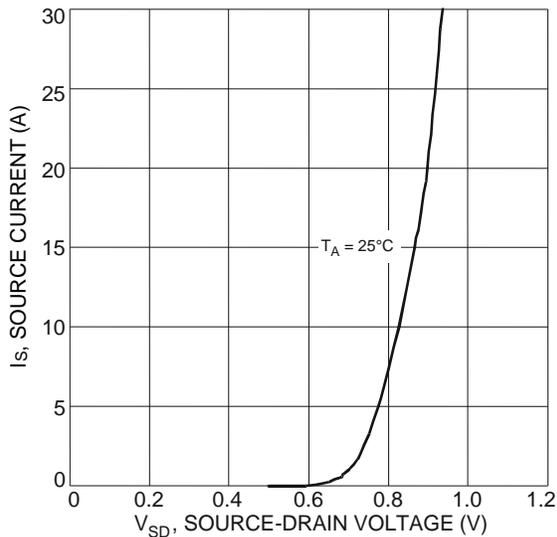


Fig.12 Diode Forward Voltage vs. Current

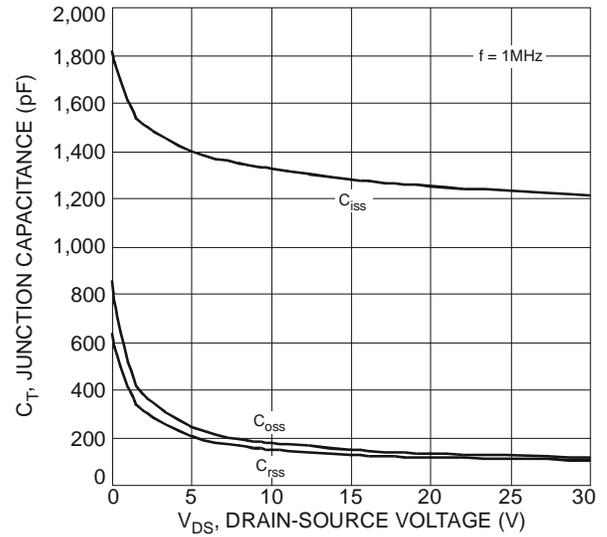


Fig. 13 Typical Junction Capacitance

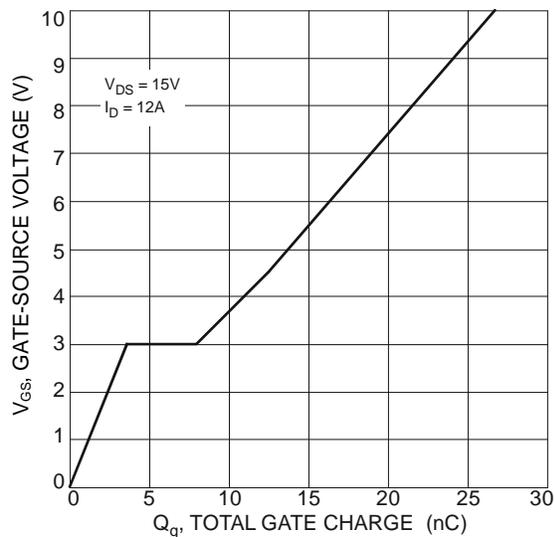


Fig. 14 Gate Charge

